544.66 LIE

CONTENTS

1.	Generation and Properties of X-Rays	1
2.	The Measurement of X-Ray Intensity, X-Ray Detectors, and Detector Systems Energy	
	Resolution	58
3.	Absorptiometry with X-Rays	127
4.	X-Ray Spectra	171
5.	The Selection of X-Ray Wavelengths	198
6.	X-Ray Diffraction in Chemical Analysis	232
7.	Measurement of Film Thickness Simple Trace Determinations	281
8.	Reliability of X-Ray Emission Spectrography Statistical Considerations	328
9.	X-Ray Emission Spectrography. General	355
10	Equipment and Selected Applications	460